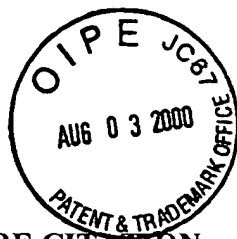


FORM PTO-1449

INFORMATION DISCLOSURE CITATION



Sheet 1 of 1
Docket No.: Bao 16-25-12
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Applicants: Bao et al.
Filing Date: 06/27/2000 Group: TBA

U.S. PATENT DOCUMENTS

EXAMINER INITIALS *	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
gzc	A	5,693,566	12/02/1997	Cheung		
gzc	B	5,773,197	06/30/1998	Carter et al.		
gzc	C	5,895,263	04/20/1999	Carter et al.		
gzc	D	5,384,376	01/24/1995	Tunney et al.		

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS *	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES / NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

gzc	E	J.L. Hedrick et al., "Toughened, Inorganic-Organic Hybrid Materials For Microelectric Application", Mat. Res. Soc. Symp. Proc., Vol. 443, Material Research Society, 1997, pp. 47-58.				
gzc	F	Chou et al., "Integration of Low k Organic Flowable SOG in a Non-Etchback/CMP Process", SPIE, Vol. 3214, 1997, pp. 86-93.				
gzc	G	Cook, Robert F. and Liniger, Eric G., "Stress-Corrosion Cracking of Low Dielectric-Constant Spin-On Glass Thin Films", <u>Electrochemical Society Proceedings</u> , Volume 98-3, pp. 129-148.				
gzc	H	Remenar, Julius, F., et al., "TEMPLATING NANOPORES INTO POLY(METHYLSILSESQUOXANE): NEW LOW-DIELECTRIC COATINGS SUITABLE FOR MICROELECTRONIC APPLICATIONS", <u>Mat. Res. Soc. Symp. Proc.</u> , Vol. 511, 1998, pp. 69-74.				
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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if in conformance and not considered. Include copy of this form with next communication to applicant.

gzc Eichen

12/31/01